Kazuki Osawa

CONTACT INFORMATION

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EDUCATION

March 2021	Tokyo Institute of Technology (Japan), Ph.D. (expected) in Computer Science
March 2018	Tokyo Institute of Technology (Japan), M.S. in Computer Science
March 2016	Tokyo Institute of Technology (Japan), B.S. in Computer Science

PREPRINTS

 Kazuki Osawa, Siddharth Swaroop, Anirudh Jain, Runa Eschenhagen, Richard E. Turner, Rio Yokota, and Mohammad Emtiyaz Khan, "Practical Deep Learning with Bayesian Principles", arXiv preprint arXiv:1906.02506, 2019. (Accepted at NeurIPS 2019.)

PUBLICATIONS (REFEREED)

- Kazuki Osawa, Yohei Tsuji, Yuichiro Ueno, Akira Naruse, Rio Yokota, and Satoshi Matsuoka.
 "Large-Scale Distributed Second-Order Optimization Using Kronecker-Factored Approximate
 Curvature for Deep Convolutional Neural Networks", IEEE/CVF Conference on Computer Vision
 and Pattern Recognition (CVPR), 2019.
- Kazuki Osawa and Rio Yokota. "Evaluating the Compression Efficiency of the Filters in Convolutional Neural Networks", Artificial Neural Networks and Machine Learning – ICANN 2017, pp 459-466, Springer 2017.
- Kazuki Osawa, Akira Sekiya, Hiroki Naganuma, Rio Yokota. "Accelerating Matrix Multiplication in Deep Learning by Using Low-Rank Approximation", 2017 International Conference on High Performance Computing & Simulation (HPCS), pp 186-192, IEEE 2017.

FELLOWSHIPS, SCHOLARSHIPS & GRANT-IN-AIDS

JSPS KAKENHI Grant Number 19J13477 (2019-2021, 1,700,000 JPY)
Research Fellow of Japan Society for the Promotion of Science (DC2) (2019-2021, 4,800,000 JPY)
A*STAR Research Attachment Programme, Singapore (2018-2019, 17,500 SGD)
The Nakajima Foundation, Ph.D. Scholarship (declined) (2018-2023, tuition and living expenses)
Japan Student Services Organization, Master's Scholarship (2016-2018, 2,112,000 JPY)
International Information Science Foundation, Overseas Dispatch of Researchers (2017, 180,000 JPY)

MEMBERSHIPS

IEEE, ACM, SIAM, IPSJ